

APPROVAL

It is hereby certified that the company

ELEMENT HOUSTON (5081583)
YORKTOWN
77040 HOUSTON - USA

is qualified for following
SPECIAL PROCESSES

- Grain size
- **Micrography**

This qualification is granted under
the conditions and restrictions defined in appendix 1

Special Processes Management

AH Laboratory

RECORD OF REVISIONS

Issue	Modified by	Description of Change / Modified pages	Date of change
-	M. SMITH ETXLL	Qualification of the following special processes: - <u>Grain size</u> - <u>Micrography</u>	05.11.2025

APPENDIX 1

SPECIAL PROCESS : GRAIN SIZE

Performed in accordance with the following documents :

Airbus Documentation :

- ASTM E112 Methods for Determining the Average Grain Size.

Supplier Documentation :

- N/A

With the following resources :

- N/A

This Qualification is based on the following results :

- Qualification program ETXLL-SPV 2024-0551
- Documentation analysis N/A
- Audit report N/A
- Action plan N/A
- AH test report N/A
- Supplier test report N/A

The Qualification is subject to the following specific conditions :

Safety class : N/A

Design applicability : AH/AHD according to L-DEV-03-022.

Restrictions :

None.

APPENDIX 1

SPECIAL PROCESS : MICROGRAPHY

Performed in accordance with the following documents :

Airbus Documentation :

- EN 3114-001 Aerospace series - Microstructure of ($\alpha+\beta$) titanium alloys wrought products - Part 1, 2, 3 and 4.
- ASTM E3 Standard Guide for Preparation of Metallographic Specimens – Micrographic examination.
- ASTM E407 Standard Practice for Microetching Metals and Alloys.

Supplier Documentation :

- N/A

With the following resources :

- N/A

This Qualification is based on the following results :

- Qualification program ETXLL-SPV 2024-0551
- Documentation analysis N/A
- Audit report N/A
- Action plan N/A
- AH test report N/A
- Supplier test report N/A

The Qualification is subject to the following specific conditions :

Safety class : N/A

Design applicability : AH/AHD according to L-DEV-03-022.

Restrictions :

None.